

# ACT<sup>™</sup> 2 Family FPGAs

## Features

- Up to 8000 Gate Array Gates (20,000 PLD equivalent gates)
- Replaces up to 200 TTL Packages
- Replaces up to eighty 20-Pin PAL<sup>®</sup> Packages
- Design Library with over 500 Macro Functions
- Single-Module Sequential Functions
- Wide-Input Combinatorial Functions
- Up to 1232 Programmable Logic Modules
- Up to 998 Flip-Flops

## **Product Family Profile**

- Datapath Performance at 105 MHz
- 16-Bit Accumulator Performance to 39 MHz
- Two In-Circuit Diagnostic Probe Pins Support Speed Analysis to 50 MHz
- Two High-Speed, Low-Skew Clock Networks
- I/O Drive to 10 mA
- Nonvolatile, User Programmable
- Logic Fully Tested Prior to Shipment
- 1.0-micron CMOS Technology

Device	A1225A	A1240A	A1280A
Capacity Gate Array Equivalent Gates PLD Equivalent Gates TTL Equivalent Packages 20-Pin PAL Equivalent Packages	2,500 6,250 63 25	4,000 10,000 100 40	8,000 20,000 200 80
Logic Modules S-Modules C-Modules	451 231 220	684 348 336	1,232 624 608
Flip-Flops (maximum)	382	568	998
Routing Resources Horizontal Tracks/Channel Vertical Tracks/Channel PLICE Antifuse Elements	36 15 250,000	36 15 400,000	36 15 750,000
User I/Os (maximum)	83	104	140
Packages <sup>1</sup>	100 CPGA 100 PQFP 100 VQFP 84 PLCC	132 CPGA 144 PQFP 176 TQFP 84 PLCC	176 CPGA 160 PQFP 176 TQFP 84 PLCC 172 CQFP
Performance <sup>2</sup> 16-Bit Prescaled Counters 16-Bit Loadable Counters 16-Bit Accumulators	105 MHz 70 MHz 39 MHz	100 MHz 69 MHz 38 MHz	85 MHz 67 MHz 36 MHz

Notes:

1. See the "Product Plan" on page 3 for package availability.

2. Performance is based on '-2' speed devices at commercial worst-case operating conditions using PREP Benchmarks, Suite #1, Version 1.2, dated 3-28-93, any analysis is not endorsed by PREP.

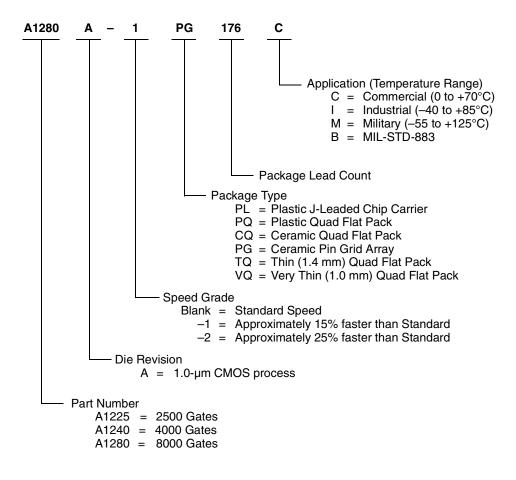


#### Description

The ACT<sup>TM</sup> 2 family represents Actel's second generation of field programmable gate arrays (FPGAs). The ACT 2 family presents a two-module architecture, consisting of C-modules and S-modules. These modules are optimized for both combinatorial and sequential designs. Based on Actel's patented channeled array architecture, the ACT 2 family provides significant enhancements to gate density and performance while maintaining downward compatibility with the ACT 1 design environment and upward compatibility with the ACT 3 design environment. The devices are implemented in silicon gate, 1.0-µm, two-level metal CMOS, and employ Actel's PLICE<sup>®</sup> antifuse technology. This revolutionary architecture offers gate array design flexibility, high performance, and fast

time-to-production with user programming. The ACT 2 family is supported by the Designer and Designer Advantage Systems, which offers automatic pin assignment, validation of electrical and design rules, automatic placement and routing, timing analysis, user programming, and diagnostic probe capabilities. The systems are supported on the following platforms:  $386/486^{\text{TM}}$  PC,  $\text{Sun}^{\text{TM}}$ , and  $\text{HP}^{\text{TM}}$  workstations. The systems provide CAE interfaces to the following design environments: Cadence, Viewlogic<sup>®</sup>, Mentor Graphics<sup>®</sup>, and OrCAD<sup>TM</sup>.

## **Ordering Information**



## **Product Plan**

	Speed	Speed Grade*			cation		
	Std	-1	-2	С	I	М	В
A1225A Device							
100-pin Ceramic Pin Grid Array (PG)	~	~	~	~			_
100-pin Plastic Quad Flat Pack (PQ)	~	~	~	~	~	_	_
100-pin Very Thin (1.0 mm) Quad Flat Pack (VQ)	~	~	~	~	—	_	_
84-pin Plastic Leaded Chip Carrier (PL)	~	~	~	~	~	_	—
A1240A Device							
132-pin Ceramic Pin Grid Array (PG)	~	~	✓	~		~	~
176-pin Thin (1.4 mm) Quad Flat Pack (TQ)	~	~	✓	~	—	_	_
144-pin Plastic Quad Flat Pack (PQ)	~	~	~	~	~	_	
84-pin Plastic Leaded Chip Carrier (PL)	~	~	~	~	~	—	—
A1280A Device							
176-pin Ceramic Pin Grid Array (PG)	~	~	<b>v</b>	<b>v</b>		~	~
176-pin Thin (1.4 mm) Quad Flat Pack (TQ)	~	~	~	~	—	_	_
160-pin Plastic Quad Flat Pack (PQ)	~	~	~	~	~	—	
172-pin Ceramic Quad Flat Pack (CQ)	~	~	~	~	_	~	~

 $Contact \ your \ Actel \ sales \ representatives \ for \ product \ availability.$  $\begin{array}{rcl} \mbox{Applications:} & C &= & Commercial & Availability: \checkmark &= & Available \\ & I &= & Industrial & P &= & Planned \\ & M &= & Military & -- &= & Not Plannee \\ & B &= & MIL-STD-883 \end{array}$ 

\*Speed Grade: -1 = Approx. 15% faster than Standard -2 = Approx. 25% faster than Standard

**Device Resources** 

.

## — = Not Planned

				User I/Os								
Davias	Logio			CPGA			PQFP		PLCC	CQFP	TQFP	VQFP
Device Series	Logic Modules	Gates	176-pin	132-pin	100-pin	160-pin	144-pin	100-pin	84-pin	172-pin	176-pin	100-pin
A1225A	451	2500	_	—	83	—	_	83	72		_	83
A1240A	684	4000	_	104		_	104	_	72	—	104	—
A1280A	1232	8000	140	_		125	_	_	72	140	140	—



## **Operating Conditions**

#### Absolute Maximum Ratings<sup>1</sup>

Free air temperature range

Symbol	Parameter	Limits	Units
V <sub>CC</sub>	DC Supply Voltage	-0.5 to +7.0	V
VI	Input Voltage	–0.5 to V <sub>CC</sub> +0.5	V
Vo	Output Voltage	–0.5 to V <sub>CC</sub> +0.5	V
I <sub>IO</sub>	I/O Source/Sink Current <sup>2</sup>	±20	mA
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C

Notes:

- 1. Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the Recommended Operating Conditions.
- 2. Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than  $V_{CC}$  + 0.5 V or less than GND 0.5 V, the internal protection diode will be forward biased and can draw excessive current.

#### **Recommended Operating Conditions**

Parameter	Commercia I	Industria I	Military	Units
Temperature Range <sup>1</sup>	0 to +70	–40 to +85	–55 to +125	°C
Power Supply Tolerance	±5	±10	±10	%V <sub>CC</sub>

Note:

1. Ambient temperature  $(T_A)$  is used for commercial and industrial; case temperature  $(T_C)$  is used for military.

		Com	mercial	Industrial		Military		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Units
V <sub>OH</sub> <sup>1</sup>	(I <sub>OH</sub> = -10 mA) <sup>2</sup>	2.4						V
	(I <sub>OH</sub> = -6 mA)	3.84						V
	(I <sub>OH</sub> = -4 mA)			3.7		3.7		V
V <sub>OL</sub> <sup>1</sup>	(I <sub>OL</sub> = 10 mA) <sup>2</sup>		0.5					V
	(I <sub>OL</sub> = 6 mA)		0.33		0.40		0.40	V
V <sub>IL</sub>		-0.3	0.8	-0.3	0.8	-0.3	0.8	V
V <sub>IH</sub>		2.0	V <sub>CC</sub> + 0.3	2.0	V <sub>CC</sub> + 0.3	2.0	V <sub>CC</sub> + 0.3	V
Input Transition	Time t <sub>R</sub> , t <sub>F</sub> <sup>2</sup>		500		500		500	ns
CIO I/O Capacita	ance <sup>2, 3</sup>		10		10		10	pF
Standby Curren	t, I <sub>CC</sub> <sup>4</sup> (typical = 1 mA)		2		10		20	mA
Leakage Currer	tt <sup>5</sup>	-10	10	-10	10	-10	10	μA

#### **Electrical Specifications**

Notes:

1. Only one output tested at a time.  $V_{CC} = min$ .

2. Not tested, for information only.

3. Includes worst-case 176 CPGA package capacitance.  $V_{OUT} = 0 V, f = 1 MHz$ .

4. All outputs unloaded. All inputs =  $V_{CC}$  or GND, typical  $I_{CC}$  = 1 mA.  $I_{CC}$  limit includes  $I_{PP}$  and  $I_{SV}$  during normal operation.

5.  $V_{OUT}$ ,  $V_{IN} = V_{CC}$  or GND.

#### **Package Thermal Characteristics**

The device junction to case thermal characteristic is  $\theta jc$ , and the junction to ambient air characteristic is  $\theta ja$ . The thermal characteristics for  $\theta ja$  are shown with two different air flow rates.

Maximum junction temperature is 150°C.

A sample calculation of the absolute maximum power dissipation allowed for a PQFP 160-pin package at commercial temperature is as follows:

Max. junction temp. (°C) – Max. commercial temp.	$=\frac{150^{\circ}\text{C}-70^{\circ}\text{C}}{24}$ W	
θja (°C/W)	$= \frac{33^{\circ}\text{C/W}}{33^{\circ}\text{C/W}} = 2.4 \text{ W}$	

Package Type	Pin Count	θјс	θja Still Air	θja 300 ft/min	Units
Tackage Type		JC		500 101111	Onits
Ceramic Pin Grid Array	100	5	35	17	°C/W
	132	5	30	15	°C/W
	176	8	23	12	°C/W
Ceramic Quad Flat Pack	172	8	25	15	°C/W
Plastic Quad Flat Pack <sup>1</sup>	100	13	48	40	°C/W
	144	15	40	32	°C/W
	160	15	38	30	°C/W
Plastic Leaded Chip Carrier <sup>2</sup>	84	12	37	28	°C/W
Very Thin Quad Flat Pack <sup>3</sup>	100	12	43	35	°C/W
Thin Quad Flat Pack <sup>4</sup>	176	15	32	25	°C/W

Notes:(Maximum Power in Still Air)

1. Maximum Power Dissipation for PQFP packages are 1.9 Watts (100-pin), 2.3 Watts (144-pin), and 2.4 Watts (160-pin).

2. Maximum Power Dissipation for PLCC packages is 2.7 Watts.

3. Maximum Power Dissipation for VQFP packages is 2.3 Watts.

4. Maximum Power Dissipation for TQFP packages is 3.1 Watts.

## **Power Dissipation**

 $P = [I_{CC} standby + I_{CC} active] * V_{CC} + I_{OL} * V_{OL} * N + I_{OH} * (V_{CC} - V_{OH}) * M$ 

Where:

 $I_{CC}\xspace$  standby is the current flowing when no inputs or outputs are changing.

 $I_{CC}$  active is the current flowing due to CMOS switching.

I<sub>OL</sub>, I<sub>OH</sub> are TTL sink/source currents.

V<sub>OL</sub>, V<sub>OH</sub> are TTL level output voltages.

N equals the number of outputs driving TTL loads to V<sub>OL</sub>.

M equals the number of outputs driving TTL loads to V<sub>OH</sub>.

An accurate determination of N and M is problematical because their values depend on the family type, design details, and on the system I/O. The power can be divided into two components: static and active.

#### **Static Power Component**

Actel FPGAs have small static power components that result in lower power dissipation than PALs or PLDs. By integrating multiple PALs/PLDs into one FPGA, an even greater reduction in board-level power dissipation can be achieved.

The power due to standby current is typically a small component of the overall power. Standby power is calculated below for commercial, worst case conditions.

I <sub>CC</sub>	V <sub>CC</sub>	Power
2 mA	5.25V	10.5 mW

The static power dissipated by TTL loads depends on the number of outputs driving high or low and the DC load current. Again, this value is typically small. For instance, a 32-bit bus sinking 4 mA at 0.33 V will generate 42 mW with all outputs driving low, and 140 mW with all outputs driving high. The actual dissipation will average somewhere between as I/Os switch states with time.

#### **Active Power Component**

Power dissipation in CMOS devices is usually dominated by the active (dynamic) power dissipation. This component is frequency dependent, a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitance due to PC board traces



and load device inputs. An additional component of the active power dissipation is the totem-pole current in CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

#### Equivalent Capacitance

The power dissipated by a CMOS circuit can be expressed by the Equation 1.

Power (
$$\mu$$
W) = C<sub>EQ</sub> \* V<sub>CC</sub><sup>2</sup> \* F (1)

Where:

$$10\text{ wer}(\mu w) = 0 \text{EQ} \quad (00 \text{ I} \text{ (1)})$$

 $C_{EQ}$  is the equivalent capacitance expressed in pF.

V<sub>CC</sub> is the power supply in volts.

F is the switching frequency in MHz.

Equivalent capacitance is calculated by measuring ICC active at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency independent so that the results may be used over a wide range of operating conditions. Equivalent capacitance values are shown below.

C <sub>EQ</sub> Values for Actel FPGAs	
Modules (C <sub>EQM</sub> )	5.8
Input Buffers (C <sub>EQI</sub> )	12.9
Output Buffers (C <sub>EQO</sub> )	23.8
Routed Array Clock Buffer Loads ( $C_{EQCR}$ )	3.9

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. Equation 2 shows a piece-wise linear summation over all components.

$Power = V_{CC}^{2} * [(m * C_{EQM} * f_{m})_{modules} + (n * C_{EQI} * f_{n})_{in}]$	puts
+ $(p * (C_{EQO} + C_L) * f_p)_{outputs} + 0.5 * (q_1 * C_{EQCR} * C_{EQCR})$	-
$f_{q1}$ <sub>routed_Clk1</sub> + $(r_1 * f_{q1})$ <sub>routed_Clk1</sub> + $0.5 * (q_2 * C_{EQCR} * C_{EQCR})$	:
f <sub>q2</sub> ) <sub>routed_Clk2</sub>	
+ $(\mathbf{r}_2 * \mathbf{f}_{q2})_{\text{routed}\_Clk2}$ ]	(2)
Where	

Where:

m	= Number of logic modules switching at fm
---	---

- n = Number of input buffers switching at fn
- p = Number of output buffers switching at fp
- q1 = Number of clock loads on the first routed array clock
- q2 = Number of clock loads on the second routed array clock
- $r_1$  = Fixed capacitance due to first routed array clock

- = Fixed capacitance due to second routed array clock
- $C_{EQM}$  = Equivalent capacitance of logic modules in pF
- $C_{EQI}$  = Equivalent capacitance of input buffers in pF
- $C_{EQO}$  = Equivalent capacitance of output buffers in pF
- - = Output lead capacitance in pF

 $\mathbf{r}_2$ 

 $C_L$ 

fm

fn

fp

f<sub>a1</sub>

- = Average logic module switching rate in MHz
- = Average input buffer switching rate in MHz
- = Average output buffer switching rate in MHz
- = Average first routed array clock rate in MHz
- $f_{\alpha 2}$  = Average second routed array clock rate in MHz

## Fixed Capacitance Values for Actel FPGAs (pF)

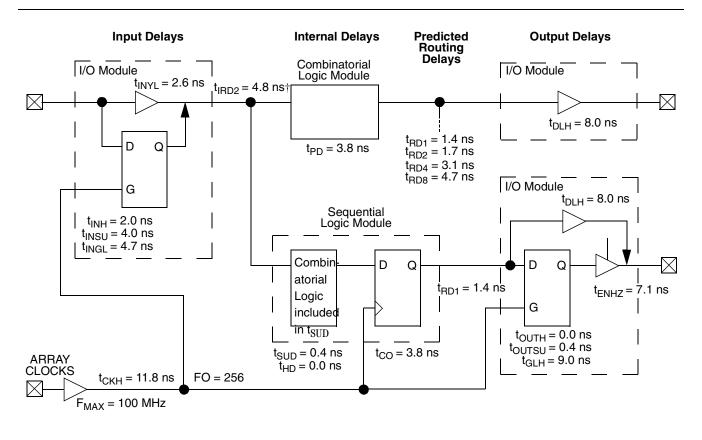
	r1	r2
Device Type	routed_Clk1	routed_Clk2
A1225A	106	106.0
A1240A	134	134.2
A1280A	168	167.8

#### **Determining Average Switching Frequency**

To determine the switching frequency for a design, you must have a detailed understanding of the data input values to the circuit. The following guidelines are meant to represent worst-case scenarios so that they can be generally used to predict the upper limits of power dissipation. These guidelines are as follows:

Logic Modules (m)	80% of modules
Inputs switching (n)	# inputs/4
Outputs switching (p)	# outputs/4
First routed array clock loads $(q_1)$	40%of sequential modules
Second routed array clock loads ( $q_2$ )	40%of sequential modules
Load capacitance (C <sub>L</sub> )	35 pF
Average logic module switching rate $(f_m)$	F/10
Average input switching rate $(f_n)$	F/5
Average output switching rate (f <sub>p</sub> )	F/10
Average first routed array clock rate $(f_{q1})$	F
Average second routed array clock rate $(f_{q2})$	F/2

## ACT 2 Timing Model\*



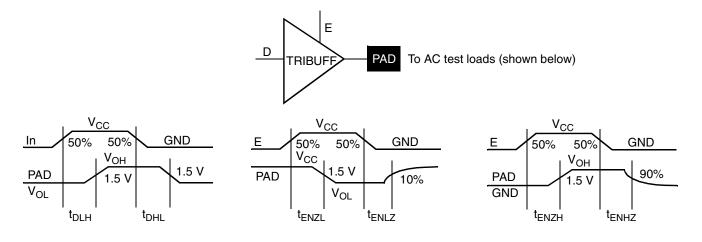
\*Values shown for A1240A-2 at worst-case commercial conditions.

† Input Module Predicted Routing Delay

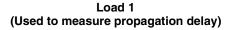


## **Parameter Measurement**

#### **Output Buffer Delays**

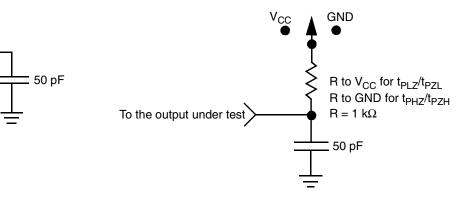


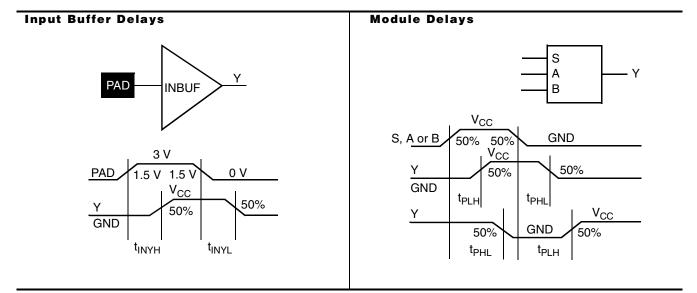
**AC** Test Loads



To the output under test

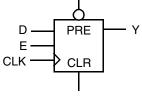
Load 2 (Used to measure rising/falling edges)



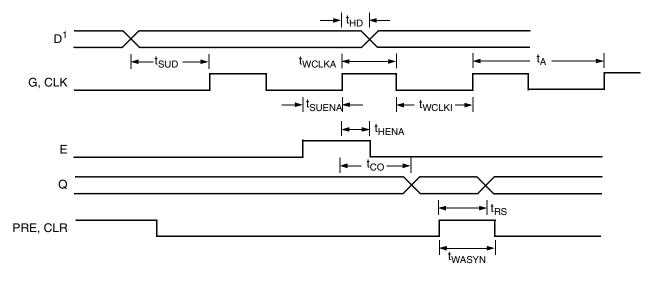


## **Sequential Module Timing Characteristics**

#### **Flip-Flops and Latches**



(Positive edge triggered)

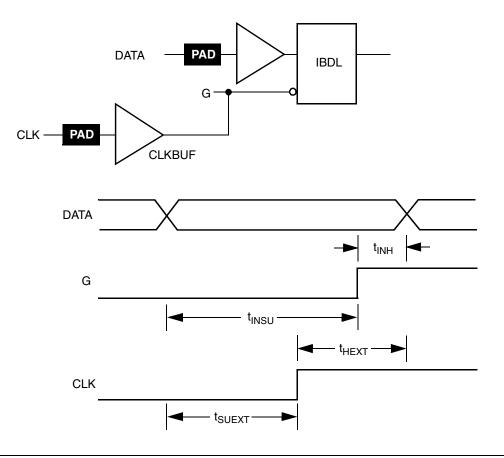


*Note:* D represents all data functions involving A, B, and S for multiplexed flip-flops.

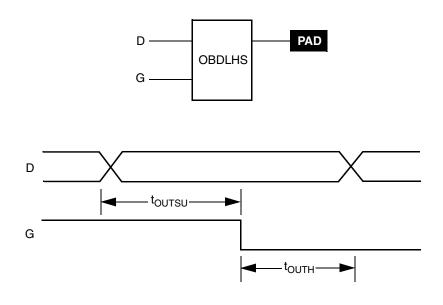


## Sequential Timing Characteristics (continued)

## Input Buffer Latches



## **Output Buffer Latches**



## Timing Derating Factor (Temperature and Voltage)

	Indu	strial	Mili	tary
	Min.	Max.	Min.	Max.
(Commercial Minimum/Maximum Specification) x	0.69	1.11	0.67	1.23

## Timing Derating Factor for Designs at Typical Temperature ( $T_J = 25^{\circ}C$ ) and Voltage (5.0 V)

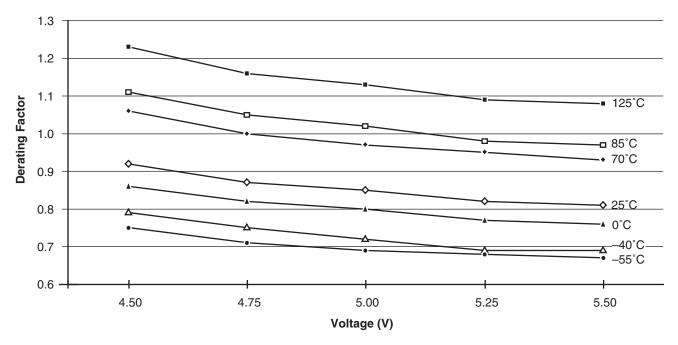
(Commercial Maximum Specification) x

0.85

## Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, $T_J = 4.75 V$ , 70°C)

	-55	-40	0	25	70	85	125
4.50	0.75	0.79	0.86	0.92	1.06	1.11	1.23
4.75	0.71	0.75	0.82	0.87	1.00	1.05	1.16
5.00	0.69	0.72	0.80	0.85	0.97	1.02	1.13
5.25	0.68	0.69	0.77	0.82	0.95	0.98	1.09
5.50	0.67	0.69	0.76	0.81	0.93	0.97	1.08

## Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, $T_J = 4.75V$ , 70°C)



#### Note: This derating factor applies to all routing and propagation delays.



## **A1225A Timing Characteristics**

#### (Worst-Case Commercial Conditions, $V_{CC}$ = 4.75 V, $T_J$ = 70°C)

Logic Module	e Propagation Delays <sup>1</sup>	'–2' \$	Speed	'–1' S	Speed	'Std'	Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>PD1</sub>	Single Module		3.8		4.3		5.0	ns
$t_{CO}$	Sequential Clk to Q		3.8		4.3		5.0	ns
$t_{GO}$	Latch G to Q		3.8		4.3		5.0	ns
$t_{RS}$	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
Predicted Ro	outing Delays <sup>2</sup>							
t <sub>RD1</sub>	FO=1 Routing Delay		1.1		1.2		1.4	ns
t <sub>RD2</sub>	FO=2 Routing Delay		1.7		1.9		2.2	ns
t <sub>RD3</sub>	FO=3 Routing Delay		2.3		2.6		3.0	ns
t <sub>RD4</sub>	FO=4 Routing Delay		2.8		3.1		3.7	ns
t <sub>RD8</sub>	FO=8 Routing Delay		4.4		4.9		5.8	ns
Sequential Ti	iming Characteristics <sup>3,4</sup>							
t <sub>SUD</sub>	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t <sub>HD</sub>	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t <sub>SUENA</sub>	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t <sub>HENA</sub>	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width	4.5		5.0		6.0		ns
t <sub>WASYN</sub>	Flip-Flop (Latch) Asynchronous Pulse Width	4.5		5.0		6.0		ns
t <sub>A</sub>	Flip-Flop Clock Input Period	9.4		11.0		13.0		ns
t <sub>INH</sub>	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t <sub>OUTH</sub>	Output Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>outsu</sub>	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f <sub>MAX</sub>	Flip-Flop (Latch) Clock Frequency		105.0		90.0		75.0	MHz

Notes:

1. For dual-module macros, use  $t_{PD1} + t_{RD1} + t_{PDn}$ ,  $t_{CO} + t_{RD1} + t_{PDn}$  or  $t_{PD1} + t_{RD1} + t_{SUD}$ , whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.

4. Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

## **A1225A Timing Characteristics (continued)**

#### (Worst-Case Commercial Conditions)

Input Module	e Propagation Delays		'–2' \$	Speed	'–1' \$	Speed	'Std'	Speed	
Parameter	Description		Min.	Max.	Min.	Max.	Min.	Max.	Unit s
t <sub>INYH</sub>	Pad to Y High			2.9		3.3		3.8	ns
t <sub>INYL</sub>	Pad to Y Low			2.6		3.0		3.5	ns
t <sub>INGH</sub>	G to Y High			5.0		5.7		6.6	ns
t <sub>INGL</sub>	G to Y Low			4.7		5.4		6.3	ns
Input Module	e Predicted Routing Delay	′s <sup>1</sup>							
t <sub>IRD1</sub>	FO=1 Routing Delay			4.1		4.6		5.4	ns
t <sub>IRD2</sub>	FO=2 Routing Delay			4.6		5.2		6.1	ns
t <sub>IRD3</sub>	FO=3 Routing Delay			5.3		6.0		7.1	ns
t <sub>IRD4</sub>	FO=4 Routing Delay			5.7		6.4		7.6	ns
t <sub>IRD8</sub>	FO=8 Routing Delay			7.4		8.3		9.8	ns
Global Clock	k Network								
t <sub>СКН</sub>	Input Low to High	FO = 32 FO = 256		10.2 11.8		11.0 13.0		12.8 15.7	ns
t <sub>CKL</sub>	Input High to Low	FO = 32 FO = 256		10.2 12.0		11.0 13.2		12.8 15.9	ns
t <sub>PWH</sub>	Minimum Pulse Width High	FO = 32 FO = 256	3.4 3.8		4.1 4.5		4.5 5.0		ns
t <sub>PWL</sub>	Minimum Pulse Width Low	FO = 32 FO = 256	3.4 3.8		4.1 4.5		4.5 5.0		ns
t <sub>CKSW</sub>	Maximum Skew	FO = 32 FO = 256		0.7 3.5		0.7 3.5		0.7 3.5	ns
t <sub>SUEXT</sub>	Input Latch External Setup	FO = 32 FO = 256	0.0 0.0		0.0 0.0		0.0 0.0		ns
t <sub>HEXT</sub>	Input Latch External Hold	FO = 32 FO = 256	7.0 11.2		7.0 11.2		7.0 11.2		ns
t <sub>P</sub>	Minimum Period	FO = 32 FO = 256	7.7 8.1		8.3 8.8		9.1 10.0		ns
f <sub>MAX</sub>	Maximum Frequency	FO = 32 FO = 256		130.0 125.0		120.0 115.0		110.0 100.0	MHz

Note:

1. These parameters should be used for estimating device performance. Optimization techniques may further reduce delays by 0 to 4 ns. Routing delays are for typical designs across worst-case operating conditions. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.



## A1225A Timing Characteristics (continued)

## (Worst-Case Commercial Conditions)

Output Modu	le Timing	'–2' S	Speed	'–1' S	Speed	'Std' S	Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output N	Nodule Timing <sup>1</sup>							
t <sub>DLH</sub>	Data to Pad High		8.0		9.0		10.6	ns
t <sub>DHL</sub>	Data to Pad Low		10.1		11.4		13.4	ns
t <sub>ENZH</sub>	Enable Pad Z to High		8.9		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.6		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.3		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		8.9		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.2		12.7		14.9	ns
$d_TLH$	Delta Low to High		0.07		0.08		0.09	ns/pF
d <sub>THL</sub>	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Outpu	It Module Timing <sup>1</sup>							
t <sub>DLH</sub>	Data to Pad High		10.1		11.5		13.5	ns
t <sub>DHL</sub>	Data to Pad Low		8.4		9.6		11.2	ns
t <sub>ENZH</sub>	Enable Pad Z to High		8.9		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.6		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.3		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		8.9		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.2		12.7		14.9	ns
d <sub>TLH</sub>	Delta Low to High		0.12		0.13		0.16	ns/pF
d <sub>THL</sub>	Delta High to Low		0.09		0.10		0.12	ns/pF

Note:

1. Delays based on 50 pF loading.

## **A1240A Timing Characteristics**

#### (Worst-Case Commercial Conditions, $V_{CC}$ = 4.75 V, $T_{J}$ = 70°C)

Logic Modu	le Propagation Delays <sup>1</sup>	'–2' \$	Speed	'–1' S	Speed	'Std'	Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>PD1</sub>	Single Module		3.8		4.3		5.0	ns
t <sub>CO</sub>	Sequential Clk to Q		3.8		4.3		5.0	ns
t <sub>GO</sub>	Latch G to Q		3.8		4.3		5.0	ns
t <sub>RS</sub>	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
Predicted R	outing Delays <sup>2</sup>							
t <sub>RD1</sub>	FO=1 Routing Delay		1.4		1.5		1.8	ns
t <sub>RD2</sub>	FO=2 Routing Delay		1.7		2.0		2.3	ns
t <sub>RD3</sub>	FO=3 Routing Delay		2.3		2.6		3.0	ns
t <sub>RD4</sub>	FO=4 Routing Delay		3.1		3.5		4.1	ns
t <sub>RD8</sub>	FO=8 Routing Delay		4.7		5.4		6.3	ns
Sequential 1	Fiming Characteristics <sup>3, 4</sup>							
t <sub>SUD</sub>	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t <sub>HD</sub>	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t <sub>SUENA</sub>	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t <sub>HENA</sub>	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width	4.5		6.0		6.5		ns
t <sub>WASYN</sub>	Flip-Flop (Latch) Asynchronous Pulse Width	4.5		6.0		6.5		ns
t <sub>A</sub>	Flip-Flop Clock Input Period	9.8		12.0		15.0		ns
t <sub>INH</sub>	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t <sub>OUTH</sub>	Output Buffer Latch Hold	0.0		0.0		0.0		ns
toutsu	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f <sub>MAX</sub>	Flip-Flop (Latch) Clock Frequency		100.0		80.0		66.0	MHz

Notes:

1. For dual-module macros, use  $t_{PD1} + t_{RD1} + t_{PDn}$ ,  $t_{CO} + t_{RD1} + t_{PDn}$  or  $t_{PD1} + t_{RD1} + t_{SUD}$ , whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.

4. Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.



## **A1240A Timing Characteristics (continued)**

### (Worst-Case Commercial Conditions)

Input Modul	e Propagation Delays		'–2' \$	Speed	'–1' \$	Speed	'Std'	Speed	
Parameter	Description		Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>INYH</sub>	Pad to Y High			2.9		3.3		3.8	ns
t <sub>INYL</sub>	Pad to Y Low			2.6		3.0		3.5	ns
t <sub>INGH</sub>	G to Y High			5.0		5.7		6.6	ns
t <sub>INGL</sub>	G to Y Low			4.7		5.4		6.3	ns
Input Modul	e Predicted Routing Delays	1							
t <sub>IRD1</sub>	FO=1 Routing Delay			4.2		4.8		5.6	ns
t <sub>IRD2</sub>	FO=2 Routing Delay			4.8		5.4		6.4	ns
t <sub>IRD3</sub>	FO=3 Routing Delay			5.4		6.1		7.2	ns
t <sub>IRD4</sub>	FO=4 Routing Delay			5.9		6.7		7.9	ns
t <sub>IRD8</sub>	FO=8 Routing Delay			7.9		8.9		10.5	ns
Global Cloc	k Network								
t <sub>CKH</sub>	Input Low to High	FO = 32 FO = 256		10.2 11.8		11.0 13.0		12.8 15.7	ns
t <sub>CKL</sub>	Input High to Low	FO = 32 FO = 256		10.2 12.0		11.0 13.2		12.8 15.9	ns
t <sub>PWH</sub>	Minimum Pulse Width High	FO = 32 FO = 256	3.8 4.1		4.5 5.0		5.5 5.8		ns
t <sub>PWL</sub>	Minimum Pulse Width Low	FO = 32 FO = 256	3.8 4.1		4.5 5.0		5.5 5.8		ns
t <sub>CKSW</sub>	Maximum Skew	FO = 32 FO = 256		0.5 2.5		0.5 2.5		0.5 2.5	ns
t <sub>SUEXT</sub>	Input Latch External Setup	FO = 32 FO = 256	0.0 0.0		0.0 0.0		0.0 0.0		ns
t <sub>HEXT</sub>	Input Latch External Hold	FO = 32 FO = 256	7.0 11.2		7.0 11.2		7.0 11.2		ns
t <sub>P</sub>	Minimum Period	FO = 32 FO = 256	8.1 8.8		9.1 10.0		11.1 11.7		ns
f <sub>MAX</sub>	Maximum Frequency	FO = 32 FO = 256		125.0 115.0		110.0 100.0		90.0 85.0	MHz

Note:

These parameters should be used for estimating device performance. Optimization techniques may further reduce delays by 0 to 4 ns. Routing delays are for typical designs across worst-case operating conditions. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

## **A1240A Timing Characteristics (continued)**

## (Worst-Case Commercial Conditions)

Output Modu	Ile Timing	'–2' \$	Speed	'–1' \$	Speed	'Std' S	Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output M	<i>Nodule Timing</i> <sup>1</sup>							
t <sub>DLH</sub>	Data to Pad High		8.0		9.0		10.6	ns
t <sub>DHL</sub>	Data to Pad Low		10.1		11.4		13.4	ns
t <sub>ENZH</sub>	Enable Pad Z to High		8.9		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.7		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.4		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		9.0		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.2		12.7		14.9	ns
d <sub>TLH</sub>	Delta Low to High		0.07		0.08		0.09	ns/pF
d <sub>THL</sub>	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Output	It Module Timing <sup>1</sup>							
t <sub>DLH</sub>	Data to Pad High		10.2		11.5		13.5	ns
t <sub>DHL</sub>	Data to Pad Low		8.4		9.6		11.2	ns
t <sub>ENZH</sub>	Enable Pad Z to High		8.9		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.7		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.4		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		9.0		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.2		12.7		14.9	ns
d <sub>TLH</sub>	Delta Low to High		0.12		0.13		0.16	ns/pF
d <sub>THL</sub>	Delta High to Low		0.09		0.10		0.12	ns/pF

Note:

1. Delays based on 50 pF loading.



## **A1280A Timing Characteristics**

#### (Worst-Case Commercial Conditions, $V_{CC}$ = 4.75 V, $T_J$ = 70°C)

Logic Module	e Propagation Delays <sup>1</sup>	'–2' \$	Speed	' <b>–</b> 1' S	Speed	'Std'	Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>PD1</sub>	Single Module		3.8		4.3		5.0	ns
t <sub>CO</sub>	Sequential Clk to Q		3.8		4.3		5.0	ns
t <sub>GO</sub>	Latch G to Q		3.8		4.3		5.0	ns
t <sub>RS</sub>	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
Predicted Ro	uting Delays <sup>2</sup>							
t <sub>RD1</sub>	FO=1 Routing Delay		1.7		2.0		2.3	ns
t <sub>RD2</sub>	FO=2 Routing Delay		2.5		2.8		3.3	ns
t <sub>RD3</sub>	FO=3 Routing Delay		3.0		3.4		4.0	ns
t <sub>RD4</sub>	FO=4 Routing Delay		3.7		4.2		4.9	ns
t <sub>RD8</sub>	FO=8 Routing Delay		6.7		7.5		8.8	ns
Sequential Ti	ming Characteristics <sup>3,4</sup>							
t <sub>SUD</sub>	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t <sub>HD</sub>	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t <sub>SUENA</sub>	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t <sub>HENA</sub>	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width	5.5		6.0		7.0		ns
t <sub>WASYN</sub>	Flip-Flop (Latch) Asynchronous Pulse Width	5.5		6.0		7.0		ns
t <sub>A</sub>	Flip-Flop Clock Input Period	11.7		13.3		18.0		ns
t <sub>INH</sub>	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t <sub>OUTH</sub>	Output Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>OUTSU</sub>	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f <sub>MAX</sub>	Flip-Flop (Latch) Clock Frequency		85.0		75.0		50.0	MHz

Notes:

1. For dual-module macros, use  $t_{PD1} + t_{RD1} + t_{PDn}$ ,  $t_{CO} + t_{RD1} + t_{PDn}$ , or  $t_{PD1} + t_{RD1} + t_{SUD}$ , whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.

4. Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

## **A1280A Timing Characteristics (continued)**

#### (Worst-Case Commercial Conditions)

Input Modu	le Propagation Delays		'–2' \$	Speed	'–1' \$	Speed	'Std'	Speed	
Parameter	Description		Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>INYH</sub>	Pad to Y High			2.9		3.3		3.8	ns
t <sub>INYL</sub>	Pad to Y Low			2.7		3.0		3.5	ns
t <sub>INGH</sub>	G to Y High			5.0		5.7		6.6	ns
t <sub>INGL</sub>	G to Y Low			4.8		5.4		6.3	ns
Input Modu	e Predicted Routing Delays	1							
t <sub>IRD1</sub>	FO=1 Routing Delay			4.6		5.1		6.0	ns
t <sub>IRD2</sub>	FO=2 Routing Delay			5.2		5.9		6.9	ns
t <sub>IRD3</sub>	FO=3 Routing Delay			5.6		6.3		7.4	ns
t <sub>IRD4</sub>	FO=4 Routing Delay			6.5		7.3		8.6	ns
t <sub>IRD8</sub>	FO=8 Routing Delay			9.4		10.5		12.4	ns
Global Cloc	k Network								
t <sub>CKH</sub>	Input Low to High	FO = 32 FO = 384		10.2 13.1		11.0 14.6		12.8 17.2	ns
t <sub>CKL</sub>	Input High to Low	FO = 32 FO = 384		10.2 13.3		11.0 14.9		12.8 17.5	ns
t <sub>PWH</sub>	Minimum Pulse Width High	FO = 32 FO = 384	5.0 5.8		5.5 6.4		6.6 7.6		ns
t <sub>PWL</sub>	Minimum Pulse Width Low	FO = 32 FO = 384	5.0 5.8		5.5 6.4		6.6 7.6		ns
t <sub>CKSW</sub>	Maximum Skew	FO = 32 FO = 384		0.5 2.5		0.5 2.5		0.5 2.5	ns
t <sub>SUEXT</sub>	Input Latch External Setup	FO = 32 FO = 384	0.0 0.0		0.0 0.0		0.0 0.0		ns
t <sub>HEXT</sub>	Input Latch External Hold	FO = 32 FO = 384	7.0 11.2		7.0 11.2		7.0 11.2		ns
t <sub>P</sub>	Minimum Period	FO = 32 FO = 384	9.6 10.6		11.2 12.6		13.3 15.3		ns
f <sub>MAX</sub>	Maximum Frequency	FO = 32 FO = 384		105.0 95.0		90.0 80.0		75.0 65.0	MHz

Note:

These parameters should be used for estimating device performance. Optimization techniques may further reduce delays by 0 to 4 ns. Routing delays are for typical designs across worst-case operating conditions. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.



## A1280A Timing Characteristics (continued)

## (Worst-Case Commercial Conditions)

Output Module Timing		'–2' Sp	eed	'–1' Sp	'-1' Speed		'Std' Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output	Nodule Timing <sup>1</sup>							
t <sub>DLH</sub>	Data to Pad High		8.1		9.0		10.6	ns
t <sub>DHL</sub>	Data to Pad Low		10.2		11.4		13.4	ns
t <sub>ENZH</sub>	Enable Pad Z to High		9.0		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.8		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.4		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		9.0		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.3		12.7		14.9	ns
$d_{TLH}$	Delta Low to High		0.07		0.08		0.09	ns/pF
d <sub>THL</sub>	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Outpu	It Module Timing <sup>1</sup>							
t <sub>DLH</sub>	Data to Pad High		10.3		11.5		13.5	ns
t <sub>DHL</sub>	Data to Pad Low		8.5		9.6		11.2	ns
t <sub>ENZH</sub>	Enable Pad Z to High		9.0		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.8		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.4		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		9.0		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.3		12.7		14.9	ns
$d_{TLH}$	Delta Low to High		0.12		0.13		0.16	ns/pF
d <sub>THL</sub>	Delta High to Low		0.09		0.10		0.12	ns/pF

Note:

1. Delays based on 50 pF loading.

2. SSO information can be found at http://www.actel.com/support/appnotes/appnotes\_design.html#board.

#### **Pin Description**

#### CLKA Clock A (Input)

TTL Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

## CLKB Clock B (Input)

TTL Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

#### DCLK Diagnostic Clock (Input)

TTL Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

#### GND Ground

LOW supply voltage.

#### I/O Input/Output (Input, Output)

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are automatically driven LOW by the ALS software.

#### MODE Mode (Input)

The MODE pin controls the use of multifunction pins (DCLK, PRA, PRB, SDI). When the MODE pin is HIGH, the special functions are active. When the MODE pin is LOW, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled high when required.

#### NC No Connection

This pin is not connected to circuitry within the device.

#### PRA Probe A (Output)

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin is used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

#### PRB Probe B (Output)

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin is used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

#### SDI Serial Data Input (Input)

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

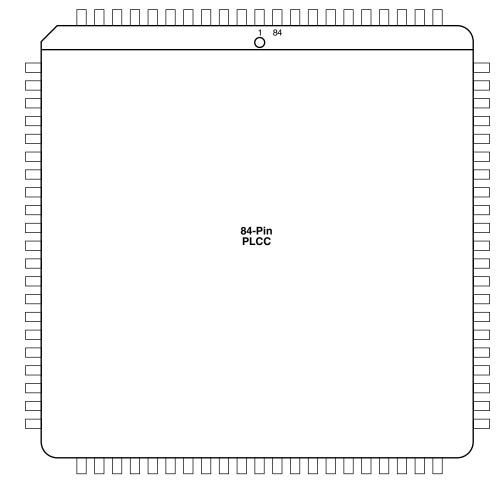
#### V<sub>CC</sub> 5.0V Supply Voltage

HIGH supply voltage.



## **Package Pin Assignments**

## 84-Pin PLCC



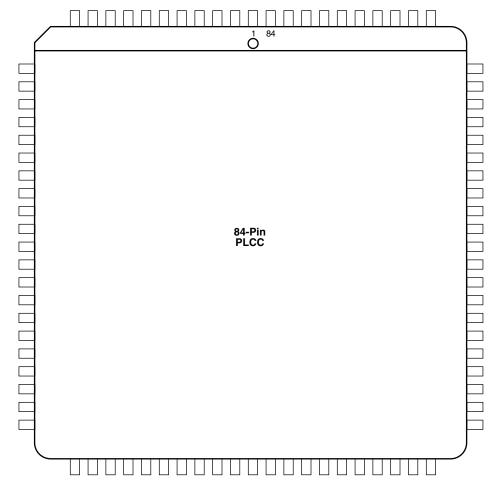
Signal	A1225A Function	A1240A Function	A1280A Function
2	CLKB, I/O	CLKB, I/O	CLKB, I/O
4	PRB, I/O	PRB, I/O	PRB, I/O
6	GND	GND	GND
10	DCLK, I/O	DCLK, I/O	DCLK, I/O
12	MODE	MODE	MODE
22	VCC	VCC	VCC
23	VCC	VCC	VCC
28	GND	GND	GND

Notes:

1. All unlisted pin numbers are user I/Os.

## **Package Pin Assignments**

## 84-Pin PLCC



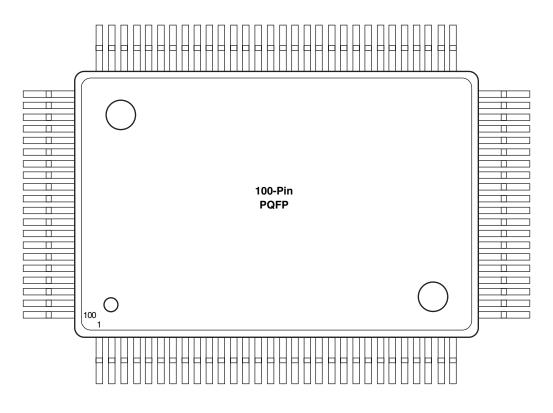
Signal	A1225A Function	A1240A Function	A1280A Function
43	VCC	VCC	VCC
49	GND	GND	GND
63	GND	GND	GND
64	VCC	VCC	VCC
65	VCC	VCC	VCC
70	GND	GND	GND
76	SDI, I/O	SDI, I/O	SDI, I/O
81	PRA, I/O	PRA, I/O	PRA, I/O
83	CLKA, I/O	CLKA, I/O	CLKA, I/O
84	VCC	VCC	VCC

#### Notes:

1. All unlisted pin numbers are user I/Os.



#### 100-Pin PQFP



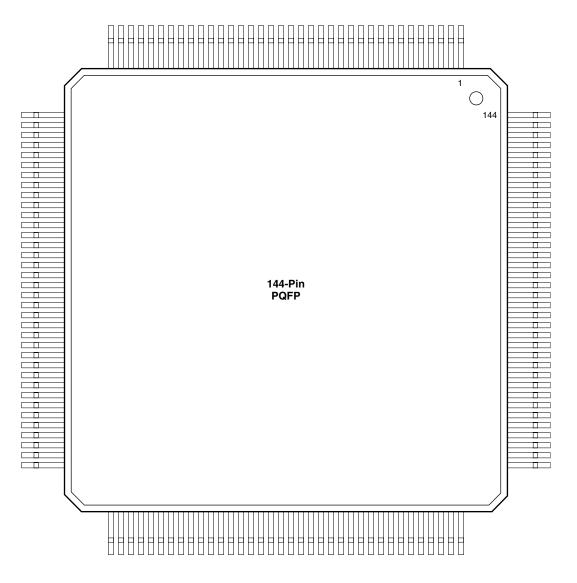
Pin Number	A1225A Function
2	DCLK, I/O
4	MODE
9	GND
16	VCC
17	VCC
22	GND
34	GND
40	VCC
46	GND
57	GND
64	GND
65	VCC

Pin Number	A1225A Function
66	VCC
67	VCC
72	GND
79	SDI, I/O
84	GND
87	PRA, I/O
89	CLKA, I/O
90	VCC
92	CLKB, I/O
94	PRB, I/O
96	GND

Notes:

1. All unlisted pin numbers are user I/Os.

## 144-Pin PQFP





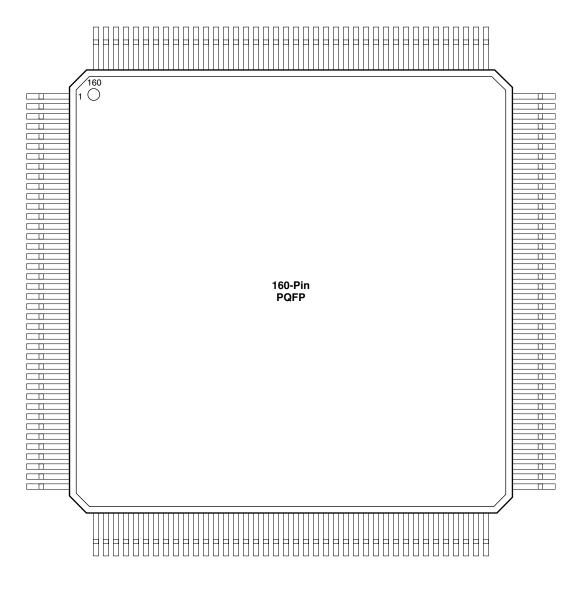
#### 144-Pin PQFP

Pin Number	A1240A Function	Pin Number	A1240A Function
2	MODE	89	VCC
9	GND	90	VCC
10	GND	91	VCC
11	GND	92	VCC
18	VCC	93	VCC
19	VCC	100	GND
20	VCC	101	GND
21	VCC	102	GND
28	GND	110	SDI, I/O
29	GND	116	GND
30	GND	117	GND
44	GND	118	GND
45	GND	123	PRA, I/O
46	GND	125	CLKA, I/O
54	VCC	126	VCC
55	VCC	127	VCC
56	VCC	128	VCC
64	GND	130	CLKB, I/O
65	GND	132	PRB, I/O
79	GND	136	GND
80	GND	137	GND
81	GND	138	GND
88	GND	144	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.

#### 160-Pin PQFP





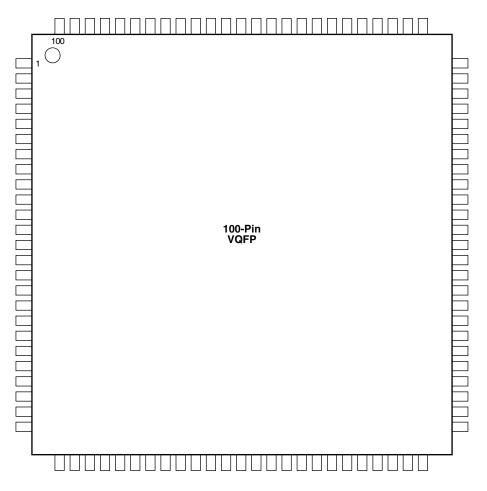
#### 160-Pin PQFP

Pin Number	A1280A Function	
2	DCLK, I/O	
6	VCC	
11	GND	
16	PRB, I/O	
18	CLKB, I/O	
20	VCC	
21	CLKA, I/O	10
23	PRA, I/O	114
30	GND	120
35	VCC	125
38	SDI, I/O	130
40	GND	135
44	GND	138
49	GND	139
54	VCC	140
57	VCC	145
58	VCC	150
59	GND	155
60	VCC	159
61	GND	160
64	GND	

Notes:

1. All unlisted pin numbers are user I/Os.

## 100-Pin VQFP



#### 100-Pin VQFP

Pin Number	A1225A Function
2	MODE
7	GND
14	VCC
15	VCC
20	GND
32	GND
38	VCC
44	GND
55	GND
62	GND
63	VCC
64	VCC

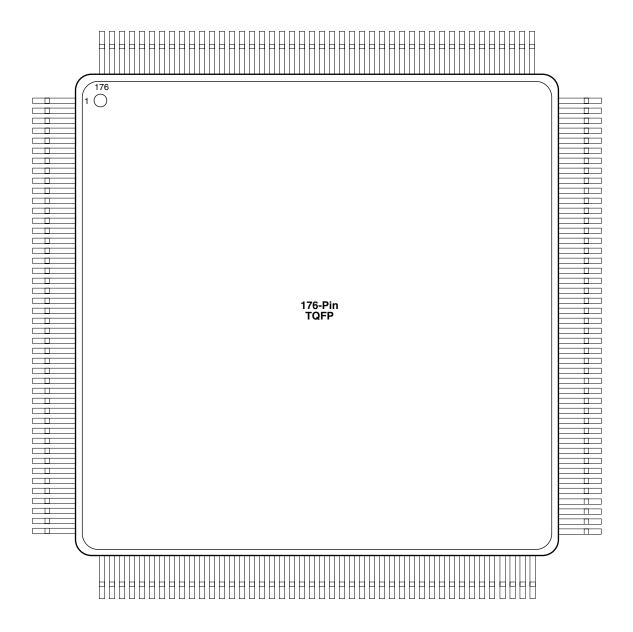
Pin Number	A1225A Function	
65	VCC	
70	GND	
77	SDI, I/O	
82	GND	
85	PRA, I/O	
87	CLKA, I/O	
88	VCC	
90	CLKB, I/O	
92	PRB, I/O	
94	GND	
100	DCLK, I/O	

Notes:

1. All unlisted pin numbers are user I/Os.



#### 176-Pin TQFP



#### 176-Pin TQFP

Pin Number	A1240A Function	A1280A Function	Pin Number	A1240A Function	A1280A Function
1	GND	GND	101	NC	NC
2	MODE	MODE	103	NC	I/O
8	NC	NC	106	GND	GND
10	NC	I/O	107	NC	I/O
11	NC	I/O	108	NC	I/O
13	NC	VCC	109	GND	GND
18	GND	GND	110	VCC	VCC
19	NC	I/O	111	GND	GND
20	NC	I/O	112	VCC	VCC
22	NC	I/O	113	VCC	VCC
23	GND	GND	114	NC	I/O
24	NC	VCC	115	NC	I/O
25	VCC	VCC	116	NC	VCC
26	NC	I/O	121	NC	NC
27	NC	I/O	124	NC	I/O
28	VCC	VCC	125	NC	I/O
29	NC	I/O	126	NC	NC
33	NC	NC	133	GND	GND
37	NC	I/O	135	SDI, I/O	SDI, I/O
38	NC	NC	136	NC	I/O
45	GND	GND	140	NC	VCC
52	NC	VCC	143	NC	I/O
54	NC	I/O	144	NC	I/O
55	NC	I/O	145	NC	NC
57	NC	NC	147	NC	I/O
61	NC	I/O	151	NC	I/O
64	NC	I/O	152	PRA, I/O	PRA, I/O
66	NC	I/O	154	CLKA, I/O	CLKA, I/O
67	GND	GND	155	VCC	VCC
68	VCC	VCC	156	GND	GND
74	NC	I/O	158	CLKB, I/O	CLKB, I/O
77	NC	NC	160	PRB, I/O	PRB, I/O
78	NC	I/O	161	NC	I/O
80	NC	I/O	165	NC	NC
82	NC	VCC	166	NC	I/O
86	NC	I/O	168	NC	I/O
89	GND	GND	170	NC	VCC
96	NC	I/O	173	NC	I/O
97	NC	I/O	175	DCLK, I/O	DCLK, I/O

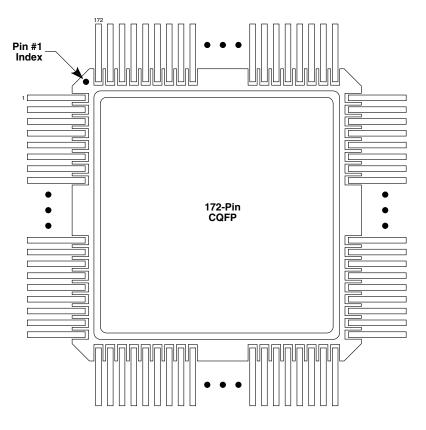
Notes:

1. NC: Denotes No Connection

2. All unlisted pin numbers are user I/Os.



## 172-Pin CQFP

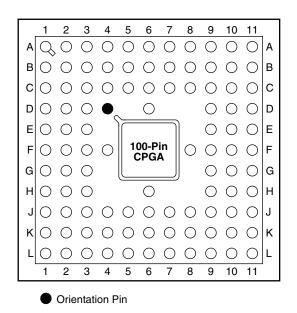


#### 172-Pin CQFP

Pin Number	A1280A Function	Pin Number	A1280A Function
1	MODE	107	VCC
7	GND	108	GND
12	VCC	109	VCC
17	GND	110	VCC
22	GND	113	VCC
23	VCC	118	GND
24	VCC	123	GND
27	VCC	131	SDI, I/O
32	GND	136	VCC
37	GND	141	GND
50	VCC	148	PRA, I/O
55	GND	150	CLKA, I/O
65	GND	151	VCC
66	VCC	152	GND
75	GND	154	CLKB, I/O
80	VCC	156	PRB, I/O
98	GND	161	GND
103	GND	166	VCC
106	GND	171	DCLK, I/O

1. All unlisted pin numbers are user I/Os.

100-Pin CPGA



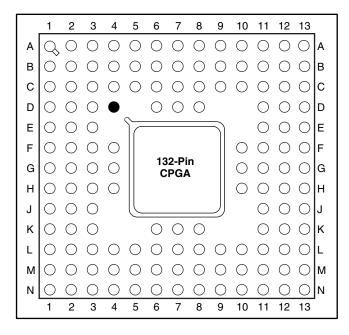
Pin Number	A1225A Function	Pin Number	A1225A Function
A4	PRB, I/O	E11	VCC
A7	PRA, I/O	F3	VCC
B6	VCC	F9	VCC
C2	MODE	F10	VCC
C3	DCLK, I/O	F11	GND
C5	GND	G1	VCC
C6	CLKA, I/O	G3	GND
C7	GND	G9	GND
C8	SDI, I/O	J5	GND
D6	CLKB, I/O	J7	GND
D10	GND	К6	VCC
E3	GND		

Note:

1. All unlisted pin numbers are user I/Os.



## 132-Pin CPGA



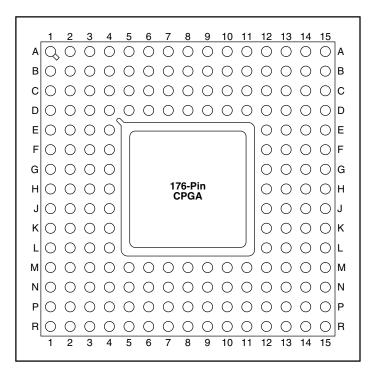
Orientation Pin

Pin Number	A1240A Function	Pin Number	A1240A Function
A1	MODE	G2	VCC
B5	GND	G3	VCC
B6	CLKB, I/O	G4	VCC
B7	CLKA, I/O	G10	VCC
B8	PRA, I/O	G11	VCC
B9	GND	G12	VCC
B12	SDI, I/O	G13	VCC
C3	DCLK, I/O	H13	GND
C5	GND	J2	GND
C6	PRB, I/O	J3	GND
C7	VCC	J11	GND
C9	GND	K7	VCC
D7	VCC	K12	GND
E3	GND	L5	GND
E11	GND	L7	VCC
E12	GND	L9	GND
F4	GND	M9	GND

Notes:

1. All unlisted pin numbers are user I/Os.

#### 176-Pin CPGA



Pin Number	A1280A Function	Pin Number	A1280A Function
A9	CLKA, I/O	H2	VCC
B3	DCLK, I/O	НЗ	VCC
B8	CLKB, I/O	H4	GND
B14	SDI, I/O	H12	GND
C3	MODE	H13	VCC
C8	GND	H14	VCC
C9	PRA, I/O	J4	VCC
D4	GND	J12	GND
D5	VCC	J13	GND
D6	GND	J14	VCC
D7	PRB, I/O	К4	GND
D8	VCC	K12	GND
D10	GND	L4	GND
D11	VCC	M4	GND
D12	GND	M5	VCC
E4	GND	M6	GND
E12	GND	M8	GND
F4	VCC	M10	GND
F12	GND	M11	VCC
G4	GND	M12	GND
G12	VCC	N8	VCC

Notes:

1. All unlisted pin numbers are user I/Os.



## List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous version	<b>3</b>	
unspecified	In the 176-Pin CPGA package, pin A3 was incorrectly assigned as CLKA, I/O. A3 is a user I/O. Pin A9 is CLKA, I/O	35

#### **Data Sheet Categories**

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